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Supporting information for article:

Separation of the inelastic and elastic scattering in time-of-flight mode on the pinhole SANS diffractometer KWS-2

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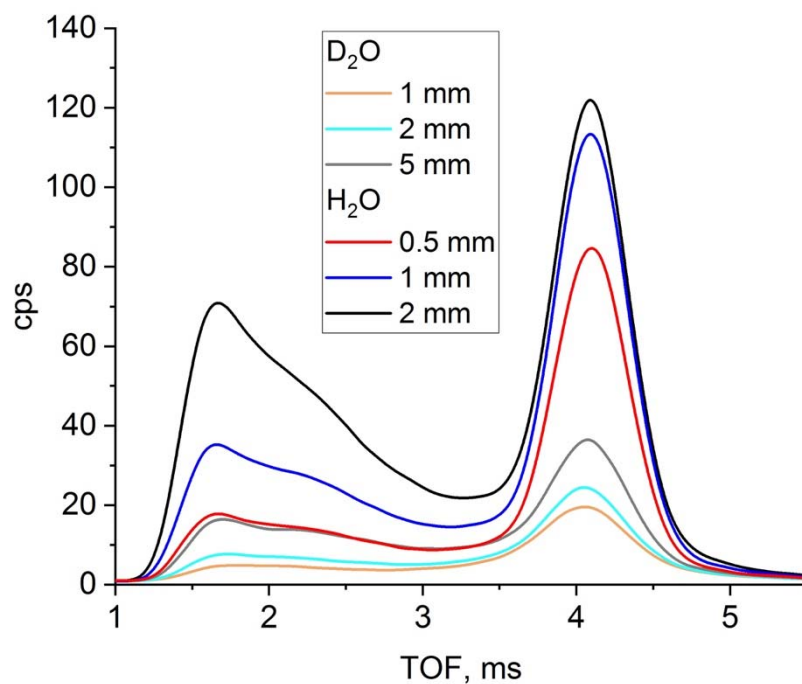


Figure S1 TOF spectra from D₂O and H₂O samples for different sample thickness t_s .

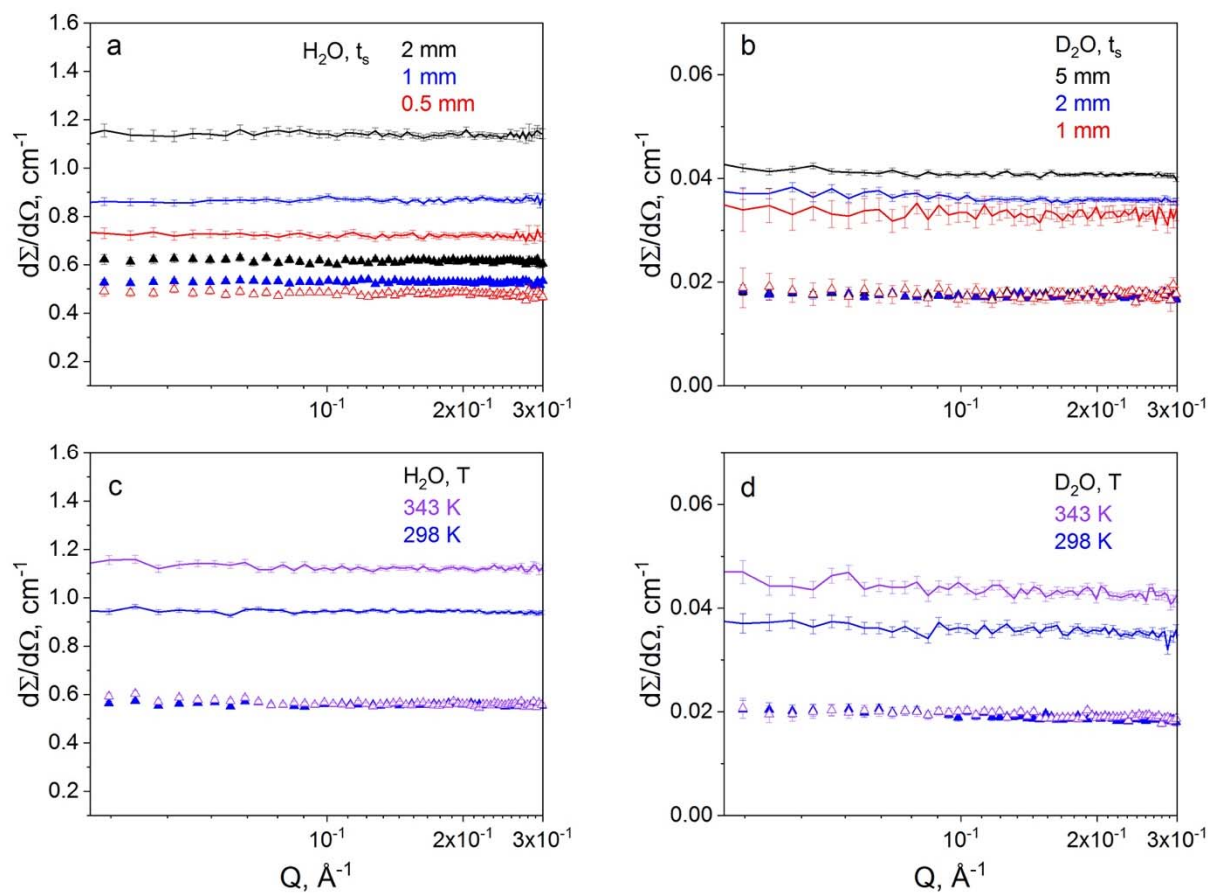


Figure S2 The data from Figure 4a,b, presented on a linear vertical axis instead of a logarithmic one.

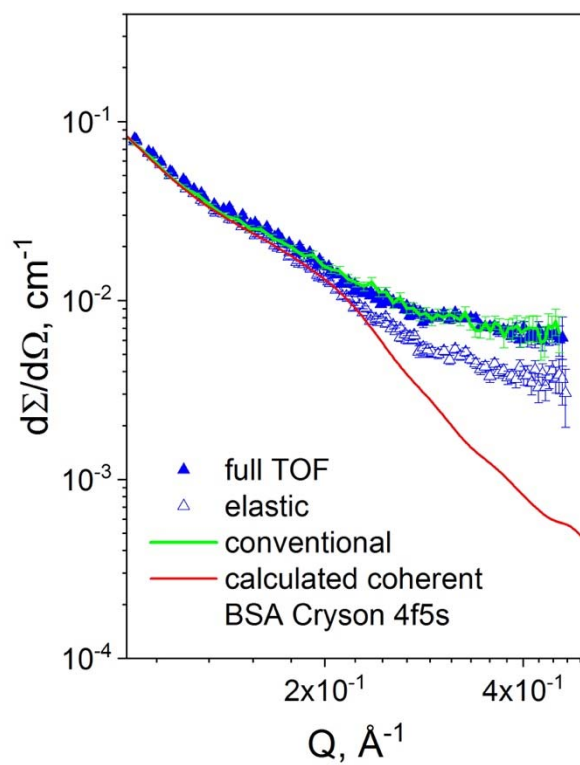


Figure S3 Measured data from BSA in D₂O solution (as in Figure 4d) together with the calculated scattering profile with CRYSON software from the atomic coordinates (PDB ID: 4f5s).